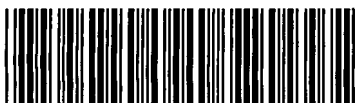


Search Notes

Application/Control No.

10/526,758

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under
Reexamination

OOYA ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	285	6/29/2007	HN
330	295	6/29/2007	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	6/29/2007	HN